

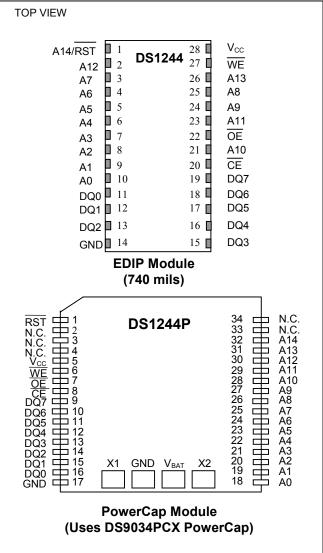
# DS1244/DS1244P 256k NV SRAM with Phantom Clock

#### FEATURES

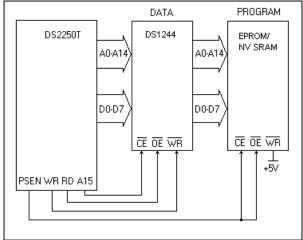
- Real-Time Clock (RTC) Keeps Track of Hundredths of Seconds, Minutes, Hours, Days, Date of the Month, Months, and Years
- 32k x 8 NV SRAM Directly Replaces Volatile Static RAM or EEPROM
- Embedded Lithium Energy Cell Maintains Calendar Operation and Retains RAM Data
- Watch Function is Transparent to RAM Operation
- Month and Year Determine the Number of Days in Each Month; Valid Up to 2100
- Full 10% Operating Range
- Operating Temperature Range: 0°C to +70°C
- Over 10 Years of Data Retention in the Absence of Power
- Lithium Energy Source is Electrically Disconnected to Retain Freshness Until Power is Applied for the First Time
- DIP Module Only
- Standard 28-Pin JEDEC Pinout
- PowerCap<sup>®</sup> Module Board Only
  - Surface Mountable Package for Direct Connection to PowerCap Containing Battery and Crystal
  - Replaceable Battery (PowerCap)
  - Pin-for-Pin Compatible with DS1248P and DS1251P
- Underwriters Laboratory (UL) Recognized
- Available in Lead-Free Package

PowerCap is a registered trademark of Dallas Semiconductor.

#### **PIN CONFIGURATIONS**



### TYPICAL OPERATING CIRCUIT



### **ORDERING INFORMATION**

PART	TEMP RANGE	PIN-PACKAGE	VOLTAGE (V)	TOP MARK
DS1244W-120	$0^{\circ}$ C to $+70^{\circ}$ C	28 EMOD (0.740a)	3.3	DS1244W-120
DS1244W-120+	$0^{\circ}$ C to $+70^{\circ}$ C	28 EMOD (0.740a)	3.3	DS1244W-120+
DS1244W-120IND	-40°C to +85°C	28 EMOD (0.740a)	3.3	DS1244W-120IND
DS1244W-120IND+	-40°C to +85°C	28 EMOD (0.740a)	3.3	DS1244W-120IND+
DS1244WP-120	$0^{\circ}$ C to $+70^{\circ}$ C	34 PowerCap*	3.3	DS1244WP-120
DS1244WP-120+	$0^{\circ}$ C to $+70^{\circ}$ C	34 PowerCap*	3.3	DS1244WP-120+
DS1244WP-120IND	-40°C to +85°C	34 PowerCap*	3.3	DS1244WP-120IND
DS1244WP-120IND+	-40°C to +85°C	34 PowerCap*	3.3	DS1244WP-120IND+
DS1244Y-70	$0^{\circ}$ C to $+70^{\circ}$ C	28 EMOD (0.740a)	5.0	DS1244Y-70
DS1244Y-70+	$0^{\circ}$ C to $+70^{\circ}$ C	28 EMOD (0.740a)	5.0	DS1244Y-70+
DS1244YP-70	$0^{\circ}$ C to $+70^{\circ}$ C	34 PowerCap*	5.0	DS1244YP-70
DS1244YP-70+	$0^{\circ}$ C to $+70^{\circ}$ C	34 PowerCap*	5.0	DS1244YP-70+

+ Denotes a lead-free/RoHS-compliant device.

\* DS9034PCX (PowerCap) required. (Must be ordered separately.)

#### DESCRIPTION

The DS1244 256k NV SRAM with a Phantom clock is a fully static nonvolatile RAM (NV SRAM) (organized as 32k words by 8 bits) with a built-in real-time clock. The DS1244 has a self-contained lithium energy source and control circuitry, which constantly monitors  $V_{CC}$  for an out-of-tolerance condition. When such a condition occurs, the lithium energy source is automatically switched on and write protection is unconditionally enabled to prevent garbled data in both the memory and real-time clock.

The phantom clock provides timekeeping information for hundredths of seconds, seconds, minutes, hours, days, date, months, and years. The date at the end of the month is automatically adjusted for months with fewer than 31 days, including correction for leap years. The phantom clock operates in either 24-hour or 12-hour format with an AM/PM indicator.

### PACKAGES

The DS1244 is available in two packages: 28-pin encapsulated DIP and 34-pin PowerCap module. The 28-pin DIP-style module integrates the crystal, lithium energy source, and silicon all in one package. The 34-pin PowerCap module board is designed with contacts for connection to a separate PowerCap (DS9034PCX) that contains the crystal and battery. This design allows the PowerCap to be mounted on top of the DS1244P after the completion of the surface mount process. Mounting the PowerCap after the surface mount process prevents damage to the crystal and battery due to the high temperatures required for solder reflow. The PowerCap is keyed to prevent reverse insertion. The PowerCap module board and PowerCap are ordered separately and shipped in separate containers. The part number for the PowerCap is DS9034PCX.

### RAM READ MODE

The DS1244 executes a read cycle whenever  $\overline{WE}$  (write enable) is inactive (high) and  $\overline{CE}$  (chip enable) is active (low). The unique address specified by the 15 address inputs (A0–A14) defines which of the 32,768 bytes of data is to be accessed. Valid data is available to the eight data-output drivers within t<sub>ACC</sub> (access time) after the last address input signal is stable, providing that  $\overline{CE}$  and  $\overline{OE}$  (output enable) access times and states are also satisfied. If  $\overline{OE}$  and  $\overline{CE}$  access times are not satisfied, then data access must be measured from the later occurring signal ( $\overline{CE}$  or  $\overline{OE}$ ) and the limiting parameter is either t<sub>CO</sub> for  $\overline{CE}$  or t<sub>OE</sub> for  $\overline{OE}$ , rather than address access.

#### RAM WRITE MODE

The DS1244 is in the write mode whenever the  $\overline{WE}$  and  $\overline{CE}$  signals are in the active (low) state after address inputs are stable. The latter occurring falling edge of  $\overline{CE}$  or  $\overline{WE}$  will determine the start of the write cycle. The write cycle is terminated by the earlier rising edge of  $\overline{CE}$  or  $\overline{WE}$ . All address inputs must be kept valid throughout the write cycle.  $\overline{WE}$  must return to the high state for a minimum recovery time (t<sub>WR</sub>) before another cycle can be initiated. The  $\overline{OE}$  control signal should be kept inactive (high) during write cycles to avoid bus contention. However, if the output bus has been enabled ( $\overline{CE}$  and  $\overline{OE}$ active) then  $\overline{WE}$  will disable the outputs in topw from its falling edge.

### **ABSOLUTE MAXIMUM RATINGS**

Voltage Range on Any Pin Relative to Ground	-0.3V to +6.0V
Storage Temperature Range	40°C to +85°C (noncondensing)
Soldering Temperature	

This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time can affect reliability.

#### **OPERATING RANGE**

RANGE	TEMP RANGE (NONCONDENSING)	V <sub>CC</sub>
Commercial	$0^{\circ}C$ to $+70^{\circ}C$	$3.3V \pm 10\%$ or $5V \pm 10\%$
Industrial	-40°C to +85°C	3.3V ±10% or 5V ±10%

#### **RECOMMENDED DC OPERATING CONDITIONS**

Over the operating range

PAR	AMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Innut Logia 1	$V_{CC} = 5V \pm 10\%$	V	2.2		$V_{CC} + 0.3V$	V	11
Input Logic 1	$V_{CC} = 5V \pm 10\%$ $V_{CC} = 3.3V \pm 10\%$	V <sub>IH</sub>	2.0		$V_{CC} + 3V$		
Innut Logio ()	$V_{CC} = 5V \pm 15\%$	V	-0.3		0.8	V	11
Input Logic 0	$V_{CC} = 3.3V \pm 10\%$	V <sub>IL</sub>	-0.3		0.6	V	11

#### **DC ELECTRICAL CHARACTERISTICS**

Over the operating range (5V)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Input Leakage Current	I <sub>IL</sub>	-1.0		+1.0	μΑ	12
I/O Leakage Current	I <sub>IO</sub>	-1.0		+1.0	μA	
$\overline{CE} \ge V_{IH} \le V_{CC}$	10	-1.0		+1.0	μΛ	
Output Current at 2.4V	I <sub>OH</sub>	-1.0			mA	
Output Current at 0.4V	I <sub>OL</sub>	2.0			mA	
Standby Current $\overline{\text{CE}} = 2.2\text{V}$	I <sub>CCS1</sub>		5	10	mA	
Standby Current	I		3.0	5.0	mA	
$\overline{\text{CE}} = \text{V}_{\text{CC}} - 0.5 \text{V}$	I <sub>CCS2</sub>		5.0	5.0	IIIA	
Operating Current $t_{CYC} = 70$ ns	I <sub>CC01</sub>			85	mA	
Write Protection Voltage	V <sub>PF</sub>	4.25	4.37	4.50	V	11
Battery Switchover Voltage	V <sub>SO</sub>		$V_{BAT}$		V	11

## DC ELECTRICAL CHARACTERISTICS

Over the operating range (3.3V)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Input Leakage Current	$I_{IL}$	-1.0		+1.0	μΑ	12
I/O Leakage Current	т	1.0		+1.0		
$\overline{CE} \ge V_{IH} \le V_{CC}$	I <sub>IO</sub>	-1.0		+1.0	μΑ	
Output Current at 2.4V	I <sub>OH</sub>	-1.0			mA	
Output Current at 0.4V	I <sub>OL</sub>	2.0			mA	
Standby Current $\overline{CE} = 2.2V$	I <sub>CCS1</sub>		5	7	mA	
Standby Current	т		2.0	2.0		
$\overline{\text{CE}} = \text{V}_{\text{CC}} - 0.5 \text{V}$	I <sub>CCS2</sub>		2.0	3.0	mA	
Operating Current $t_{CYC} = 70$ ns	I <sub>CC01</sub>			50	mA	
Write Protection Voltage	$V_{PF}$	2.80	2.86	2.97	V	11
Battery Switchover Voltage	V <sub>SO</sub>		$V_{BAT} \text{ or } V_{PF}$		V	11

#### CAPACITANCE

(T<sub>A</sub> = +25°C)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Input Capacitance	C <sub>IN</sub>		5	10	pF	
Input/Output Capacitance	C <sub>I/O</sub>		5	10	pF	

#### MEMORY AC ELECTRICAL CHARACTERISTICS

Over the operating range (5V)

PARAMETER	SYMBOL	<b>DS12</b> 4	4Y-70	UNITS	NOTES
PARAWLIEK	SINDUL	MIN	MAX	UNIIS	NULES
Read Cycle Time	t <sub>RC</sub>	70		ns	
Access Time	t <sub>ACC</sub>		70	ns	
$\overline{OE}$ to Output Valid	t <sub>OE</sub>		35	ns	
$\overline{CE}$ to Output Valid	t <sub>CO</sub>		70	ns	
$\overline{OE}$ or $\overline{CE}$ to Output Active	t <sub>COE</sub>	5		ns	5
Output High-Z from Deselection	t <sub>OD</sub>		25	ns	5
Output Hold from Address Change	t <sub>OH</sub>	5		ns	
Write Cycle Time	t <sub>WC</sub>	70		ns	
Write Pulse Width	t <sub>WP</sub>	50		ns	3
Address Setup Time	t <sub>AW</sub>	0		ns	
Write Recovery Time	t <sub>WR</sub>	0		ns	
Output High-Z from $\overline{WE}$	t <sub>ODW</sub>		25	ns	5
Output Active from WE	t <sub>OEW</sub>	5		ns	5
Data Setup Time	t <sub>DS</sub>	30		ns	4
Data Hold Time from WE	t <sub>DH</sub>	5		ns	4

### PHANTOM CLOCK AC ELECTRICAL CHARACTERISTICS

			Over the operating range (5				
PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES	
Read Cycle Time	t <sub>RC</sub>	65			ns		
$\overline{\text{CE}}$ Access Time	t <sub>CO</sub>			55	ns		
OE Access Time	t <sub>OE</sub>			55	ns		
CE to Output Low-Z	t <sub>COE</sub>	5			ns		
OE to Output Low-Z	t <sub>OEE</sub>	5			ns		
CE to Output High-Z	t <sub>OD</sub>			25	ns	5	
OE to Output High-Z	t <sub>ODO</sub>			25	ns	5	
Read Recovery	t <sub>RR</sub>	10			ns		
Write Cycle Time	t <sub>WC</sub>	65			ns		
Write Pulse Width	t <sub>WP</sub>	55			ns	3	
Write Recovery	t <sub>WR</sub>	10			ns	10	
Data Setup Time	t <sub>DS</sub>	30			ns	4	
Data Hold Time	t <sub>DH</sub>	0			ns	4	
CE Pulse Width	$t_{\rm CW}$	60			ns		
RESET Pulse Width	t <sub>RST</sub>	65			ns		

#### **POWER-DOWN/POWER-UP TIMING**

Over the operating range (5V)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
$\overline{\text{CE}}$ at V <sub>IH</sub> before Power-Down	t <sub>PD</sub>	0			μs	
V <sub>CC</sub> Slew from V <sub>PF(max)</sub> to	t <sub>F</sub>	300			μs	
$V_{PF(min)}(\overline{CE} \text{ at } V_{PF})$						
$V_{CC}$ Slew from $V_{PF(min)}$ to $V_{SO}$	t <sub>FB</sub>	10			μs	
$V_{CC}$ Slew from $V_{PF(max)}$ to	t <sub>R</sub>	0			μs	
$V_{PF(min)}(\overline{CE} \text{ at } V_{PF})$						
$\overline{CE}$ at V <sub>IH</sub> after Power-Up	t <sub>REC</sub>	1.5		2.5	ms	

 $(T_{A} = +25^{\circ}C)$ 

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Expected Data Retention Time	t <sub>DR</sub>	10			years	9

Warning: Under no circumstances are negative undershoots of any amplitude allowed when device is in battery-backup mode.

### MEMORY AC ELECTRICAL CHARACTERISTICS

Over the operating range (3.3V)

DADAMETED	SYMBOL	DS124	4W-120	UNITS	NOTES
PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
Read Cycle Time	t <sub>RC</sub>	120		ns	
Access Time	t <sub>ACC</sub>		120	ns	
$\overline{OE}$ to Output Valid	t <sub>OE</sub>		60	ns	
$\overline{CE}$ to Output Valid	t <sub>CO</sub>		120	ns	
$\overline{OE}$ or $\overline{CE}$ to Output Active	t <sub>COE</sub>	5		ns	5
Output High-Z from Deselection	t <sub>OD</sub>		40	ns	5
Output Hold from Address Change	t <sub>OH</sub>	5		ns	
Write Cycle Time	t <sub>WC</sub>	120		ns	
Write Pulse Width	t <sub>WP</sub>	90		ns	3
Address Setup Time	t <sub>AW</sub>	0		ns	
Write Recovery Time	t <sub>WR</sub>	20		ns	10
Output High-Z from $\overline{WE}$	t <sub>ODW</sub>		40	ns	5
Output Active from WE	t <sub>OEW</sub>	5		ns	5
Data Setup Time	t <sub>DS</sub>	50		ns	4
Data Hold Time from $\overline{WE}$	t <sub>DH</sub>	20		ns	4

### PHANTOM CLOCK AC ELECTRICAL CHARACTERISTICS

Over the operating range (3.3V)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
				MAA	UNITS	NULES
Read Cycle Time	t <sub>RC</sub>	120			ns	
$\overline{\text{CE}}$ Access Time	t <sub>CO</sub>			100	ns	
$\overline{OE}$ Access Time	t <sub>OE</sub>			100	ns	
CE to Output Low-Z	t <sub>COE</sub>	5			ns	
OE to Output Low-Z	t <sub>OEE</sub>	5			ns	
$\overline{CE}$ to Output High-Z	t <sub>OD</sub>			40	ns	5
$\overline{\text{OE}}$ to Output High-Z	t <sub>ODO</sub>			40	ns	5
Read Recovery	t <sub>RR</sub>	20			ns	
Write Cycle Time	t <sub>WC</sub>	120			ns	
Write Pulse Width	t <sub>WP</sub>	100			ns	3
Write Recovery	t <sub>WR</sub>	20			ns	10
Data Setup Time	t <sub>DS</sub>	45			ns	4
Data Hold Time	t <sub>DH</sub>	0			ns	4
CE Pulse Width	t <sub>CW</sub>	105			ns	
RESET Pulse Width	t <sub>RST</sub>	120			ns	

### POWER-DOWN/POWER-UP TIMING

Over the operating range (3.3V)

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
$\overline{CE}$ at V <sub>IH</sub> before Power-Down	t <sub>PD</sub>	0			μs	
$V_{CC}$ Slew from $V_{PF(MAX)}$ to	t <sub>F</sub>	300			μs	
$V_{PF(MIN)}(\overline{CE} \text{ at } V_{IH})$						
$V_{CC}$ Slew from $V_{PF(MAX)}$ to	t <sub>R</sub>	0			μs	
$V_{PF(MIN)}(\overline{CE} \text{ at } V_{IH})$						
$\overline{\text{CE}}$ at V <sub>IH</sub> after Power-Up	t <sub>REC</sub>	1.5		2.5	ms	

 $(T_{A} = +25^{\circ}C)$ 

PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Expected Data Retention Time	t <sub>DR</sub>	10			years	9

Warning: Under no circumstances are negative undershoots, of any amplitude, allowed when device is in battery-backup mode.

### **AC TEST CONDITIONS**

Output Load: 50pF + 1TTL Gate Input Pulse Levels: 0 to 3V

Timing Measurement Reference Levels Input: 1.5V Output: 1.5V Input Pulse Rise and Fall Times: 5ns

### NOTES:

- 1)  $\overline{\text{WE}}$  is high for a read cycle.
- 2)  $\overline{OE} = V_{IH}$  or  $V_{IL}$ . If  $\overline{OE} = V_{IH}$  during write cycle, the output buffers remain in a high-impedance state.
- 3)  $t_{WP}$  is specified as the logical AND of CE and WE.  $t_{WP}$  is measured from the latter of CE or WE going low to the earlier of  $\overline{CE}$  or  $\overline{WE}$  going high.
- 4)  $t_{DH}$ ,  $t_{DS}$  are measured from the earlier of  $\overline{CE}$  or  $\overline{WE}$  going high.
- 5) These parameters are sampled with a 50pF load and are not 100% tested.
- 6) If the  $\overline{CE}$  low transition occurs simultaneously with or later than the  $\overline{WE}$  low transition in Write Cycle 1, the output buffers remain in a high-impedance state during this period.
- 7) If the  $\overline{CE}$  high transition occurs prior to or simultaneously with the  $\overline{WE}$  high transition, the output buffers remain in a high-impedance state during this period.
- 8) If  $\overline{WE}$  is low or the  $\overline{WE}$  low transition occurs prior to or simultaneously with the  $\overline{CE}$  low transition, the output buffers remain in a high-impedance state during this period.
- 9) The expected  $t_{DR}$  is defined as cumulative time in the absence of  $V_{CC}$  with the clock oscillator running.
- 10)  $t_{WR}$  is a function of the latter occurring edge of  $\overline{WE}$  or  $\overline{CE}$ .
- 11) Voltages are reference to ground.
- 12)  $\overline{\text{RST}}$  (Pin 1) has an internal pullup resistor.
- 13) RTC modules can be successfully processed through conventional wave-soldering techniques as long as temperature exposure to the lithium energy source contained within does not exceed +85°C. Postsolder cleaning with water-washing techniques is acceptable, provided that ultrasonic vibration is not used.

In addition, for the PowerCap:

- 1) Dallas Semiconductor recommends that PowerCap module bases experience one pass through solder reflow oriented with the label side up ("live-bug").
- 2) Hand soldering and touch-up: Do not touch or apply the soldering iron to leads for more than three seconds.
  - To solder, apply flux to the pad, heat the lead frame pad, and apply solder. To remove the part, apply flux, heat the lead frame pad until the solder reflows, and use a solder wick to remove solder.